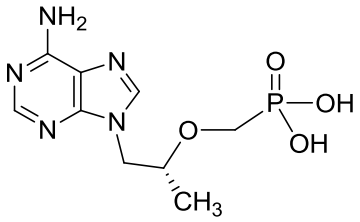
CLAIMS

1. A crystal form, Form I, of a compound:



which is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 7.5±0.2, 15.0±0.2, 22.5±0.2 and 24.8±0.2 obtained using CuKα_1 X-ray.

2. The crystal form of claim 1, having an XRPD pattern having at least 5 peaks in common with the pattern as shown in FIG. 1 wherein the at least 5 peaks in common are at ±0.2 degree of two theta angle within the peaks of FIG. 1.

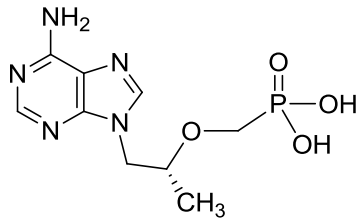
3. The crystal form of claim 1, having an XRPD pattern with peaks at ±0.2 degree of two theta angle within the peaks shown in Table 1:

No.	Pos. [°2Th.]	Rel. Int. [%]
1	7.5	49.83
2	15.0	100
3	15.5	2.91
4	16.0	6.89
5	18.2	8.87
6	18.6	1.12
7	19.4	1.67
8	22.5	32.59
9	23.4	8.77
10	24.8	34.1
11	25.2	5.25
12	26.0	1.67
13	29.0	1.93
14	29.9	5.05
15	34.6	1.12
16	35.4	0.93

17	37.8	5.67.

4. The crystal form of claim 1, characterized by a differential scanning calorimetry (DSC) thermogram comprising an endothermic event with peak maxima at about 98 °C.

5. A crystal form, Form IV, of a compound:



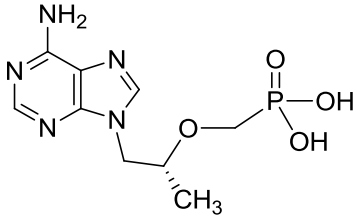
which is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 6.2±0.2, 12.4±0.2, 18.6±0.2, 24.9±0.2 and 37.7±0.2 obtained using CuKα_1 X-ray.

6. The crystal form of claim 5, having an XRPD pattern having at least 5 peaks in common with the pattern shown in FIG. 2 wherein the at least 5 peaks in common are at ±0.2 degree of two theta angle within the peaks of FIG. 2.

7. The crystal form of claim 5, having an XRPD pattern with peaks at ±0.2 degree of two theta angle within the peaks shown in Table 3:

No.	Pos. [°2Th.]	Rel. Int. [%]
1	6.2	100
2	12.4	23.04
3	14.8	0.57
4	17.0	1.72
5	18.6	5.9
6	19.8	0.8
7	24.9	18.24
8	25.4	1.34
9	26.8	1.81
10	28.2	0.81
11	31.1	0.45
12	37.7	13.5.

8. A crystal form, Form VI, of a compound:



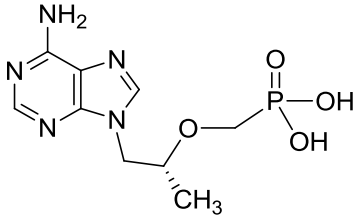
which is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 6.0±0.2, 12.0±0.2, 24.0±0.2, 24.5±0.2 and 37.6±0.2 obtained using CuKα_1 X-ray.

9. The crystal form of claim 8, having an XRPD pattern having at least 5 peaks in common with the pattern shown in FIG. 3 wherein the at least 5 peaks in common are at ±0.2 degree of two theta angle within the peaks of FIG. 3.

10. The crystal form of claim 8, having an XRPD pattern with peaks at ±0.2 degree of two theta angle within the peaks shown in Table 2:

No.	Pos. [°2Th.]	Rel. Int. [%]
1	6.0	100
2	12.0	25.45
3	12.9	1.19
4	15.5	1.7
5	18.0	2.86
6	18.6	0.34
7	20.5	2.08
8	24.0	5.92
9	24.5	4.92
10	25.2	0.98
11	25.9	3.98
12	28.2	0.78
13	30.1	3.11
14	30.5	1.86
15	31.7	0.87
16	36.2	9.12
17	36.6	1.7
18	37.6	1.86.

11. A crystal form, Form IX, of a compound:



which is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 5.9±0.2, 11.3±0.2, 16.5±0.2, 21.5±0.2, 26.1±0.2 and 26.8±0.2 obtained using CuKα_1 X-ray.

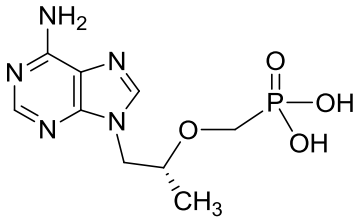
12. The crystal form of claim 11, having an XRPD pattern having at least 5 peaks in common with the pattern shown in FIG. 4 wherein the at least 5 peaks in common are at ±0.2 degree of two theta angle within the peaks of FIG. 4.

13. The crystal form of claim 11, having an XRPD pattern with peaks at ±0.2 degree of two theta angle within the peaks shown in Table 4:

No.	Pos. [°2Th.]	Rel. Int. [%]
1	5.9	31.87
2	11.3	24.78
3	14.2	17.44
4	15.4	34.56
5	16.5	71.15
6	18.5	8.02
7	19.8	34.86
8	20.4	11.71
9	21.5	61.09
10	23.7	53.51
11	25.1	54.43
12	26.1	77.04
13	23.6	8.13
14	26.8	100
15	27.2	12.3
16	27.9	13.02
17	28.6	23.86
18	29.2	17.2
19	30.4	8.12
20	31.6	13.07
21	32.0	0.26
22	32.4	11.22
23	33.5	9.33

24	35.7	3.18
25	36.0	3.24
26	36.6	2.63
27	38.1	5.68
28	38.7	2.43.

14. A composition comprising the crystal form Form I and a crystal form Form IV of a compound:

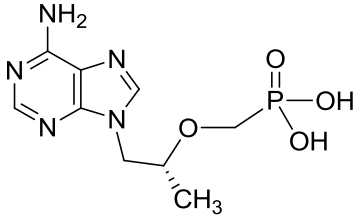


wherein

Form I is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 7.5±0.2, 15.0±0.2, 22.5±0.2 and 24.8±0.2 obtained using CuKα_1 X-ray; and

Form IV is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 6.2±0.2, 12.4±0.2, 18.6±0.2, 24.9±0.2 and 37.7±0.2 obtained using CuKα_1 X-ray.

15. A composition comprising the crystal form Form I and a crystal form Form VI of a compound:

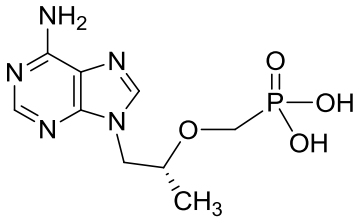


wherein

Form I is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 7.5±0.2, 15.0±0.2, 22.5±0.2 and 24.8±0.2 obtained using CuKα_1 X-ray; and

Form VI is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 6.0±0.2, 12.0±0.2, 24.0±0.2, 24.5±0.2 and 37.6±0.2 obtained using CuKα_1 X-ray.

16. A composition comprising the crystal form Form I and a crystal form Form IX of a compound:



wherein

Form I is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 7.5±0.2, 15.0±0.2, 22.5±0.2 and 24.8±0.2 obtained using CuKα_1 X-ray; and

Form IX is characterized by a X-ray powder diffraction (XRPD) pattern comprising peaks expressed in degrees of two theta angle of 5.9±0.2, 11.3±0.2, 16.5±0.2, 21.5±0.2, 26.1±0.2 and 26.8±0.2 obtained using CuKα_1 X-ray.

17. A pharmaceutical composition comprising the crystal form of claim 1.

18. The composition of claim 17 further comprising a pharmaceutically acceptable carrier or excipient.